SN54ABT16841...WD PACKAGE

SN74ABT16841 . . . DL PACKAGE

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- **Members of the Texas Instruments** Widebus™ Family
- State-of-the-Art *EPIC-IIB™* BiCMOS Design Significantly Reduces Power Dissipation
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V<sub>OLP</sub> (Output Ground Bounce) < 0.8 V at  $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$
- **High-Impedance State During Power Up** and Power Down
- Distributed V<sub>CC</sub> and GND Pin Configuration **Minimizes High-Speed Switching Noise**
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (-32-mA I<sub>OH</sub>, 64-mA I<sub>OL</sub>)
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center **Spacings**

#### description

These 20-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

(TOP VIEW) 56 U 1LE 10F 55 1D1 1Q1 **1**2 1Q2 43 54 1D2 GND 4 53 | GND 1Q3 **[**]5 52 L 1D3 1Q4 **[**]6 51 1D4 50 | V<sub>CC</sub> V<sub>CC</sub> 47 1Q5 🛮 8 49 🛮 1D5 1Q6 49 48 1 1D6 1Q7 4 10 47 **∐** 1D7 GND 🛚 11 46 | GND 1Q8 L 12 45 1D8 1Q9 13 44 L 1D9 43 🛮 1D10 1Q10 L 14 2Q1 L 15 42 2D1 2Q2 L 16 41 2D2 2Q3 [] 17 40 2D3 GND L 18 39 l gnd

19

21 2Q6 L

22  $V_{CC}$ 2Q7 🛮 23

24

27

28

2Q4 L

2Q8 L

2Q10

2OE

GND 25

2Q9 26

2Q5 **2**0

38 2D4

37 D 2D5

36 2D6

35 🛮 V<sub>CC</sub>

34 2D7

32 | GND

31 2D9

30 D 2D10

29 | 2LE

∐ 2D8

33

The 'ABT16841 can be used as two 10-bit latches or one 20-bit latch. The 20 transparent D-type latches provide true data at the outputs. While the latch-enable (1LE or 2LE) input is high, the Q outputs of the corresponding 10-bit latch follow the D inputs. When LE is taken low, the Q outputs are latched at the levels set up at the D inputs.

A buffered output-enable (1<del>OE</del> or 2<del>OE</del>) input can be used to place the outputs of the corresponding 10-bit latch in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.

The output-enable input does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.



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#### description (continued)

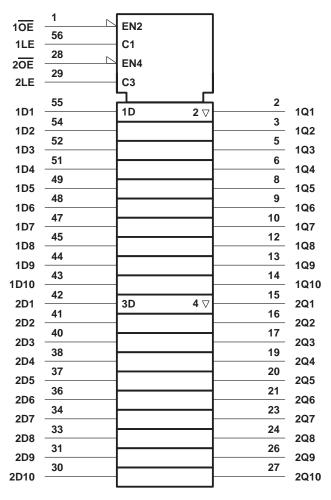
When  $V_{CC}$  is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16841 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT16841 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each 10-bit latch)

	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q <sub>0</sub>
Н	X	Χ	Z

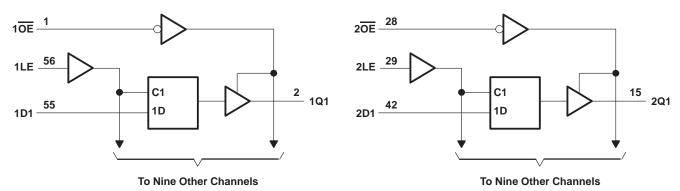
## logic symbol†



 $<sup>^\</sup>dagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



### logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V <sub>O</sub>	0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABT16841	96 mA
SN74ABT16841	128 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–18 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DL package	74°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

### recommended operating conditions (see Note 3)

			SN54AB	SN54ABT16841		SN74ABT16841		
			MIN	MAX	MIN	MAX	UNIT	
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V	
VIH	/IH High-level input voltage		2		2		V	
V <sub>IL</sub>	Low-level input voltage			0.8		0.8	V	
VI	Input voltage		0	VCC	0	VCC	V	
IOH	OH High-level output current			-24		-32	mA	
loL	Low-level output current			48		64	mA	
Δt/Δν	Input transition rise or fall rate Outputs enabled			10		10	ns/V	
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		200		200		μs/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



<sup>2.</sup> The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

Г.	PARAMETER	TEST CO	ONDITIONS	Т	A = 25°C	;	SN54AB	Γ16841	SN74AB1	UNIT		
	ARAMETER	TEST CC	DINDITIONS	MIN	TYP <sup>†</sup>	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK		$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5		2.5			
\ \/a		V <sub>CC</sub> = 5 V,	$I_{OH} = -3 \text{ mA}$	3			3		3		v	
VOH		V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -24 mA	2			2				V	
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
V/01		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA			0.55		0.55			V	
VOL		VCC = 4.5 V	I <sub>OL</sub> = 64 mA			0.55*				0.55	V	
V <sub>hys</sub>					100						mV	
١.		$V_{CC} = 0$ to 5.5 V, $V_I = V_{CC}$ or GND				±1				±1		
†į		$V_{CC} = 5 \text{ V}, V_{I} = V_{CC} \text{ or GND}$						±5			μΑ	
lozpu	<sub>J</sub> ‡	$V_{CC} = 0 \text{ to } 2.1 \text{ V},$ $V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{OE} = X$				±50		±50		±50	μА	
IOZPE	) <sup>‡</sup>	V <sub>CC</sub> = 2.1 V to 0 V <sub>O</sub> = 0.5 V to 2.7	, 7 V, <del>OE</del> = X			±50		±50		±50	μА	
lozh		$V_{CC} = 2.1 \text{ V to } 5$ $V_{O} = 2.7 \text{ V, } \overline{OE} \ge$	.5 V, 2 V			10		10		10	μА	
lozL		$V_{CC} = 2.1 \text{ V to 5}$ $V_{O} = 0.5 \text{ V}, \overline{\text{OE}} \ge$				-10		-10		-10	μΑ	
l <sub>off</sub>		$V_{CC} = 0$ ,	$V_I$ or $V_O \le 4.5 \text{ V}$			±100				±100	μΑ	
ICEX	Outputs high	$V_{CC} = 5.5 \text{ V},$	$V_0 = 5.5 \text{ V}$			50		50		50	μΑ	
IO§		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.5 \text{ V}$	-50	-100	-180	-50	-180	-50	-180	mA	
	Outputs high					0.5		0.5				
ICC	Outputs low	$V_{CC} = 5.5 \text{ V, I}_{O} = V_{CC} \text{ or GNI}$			89		89		89	mA		
	Outputs disabled	utputs disabled				0.5		0.5		0.5		
ΔICC¶		V <sub>CC</sub> = 5.5 V, One Other inputs at V				1.5		1.5		1.5	mA	
Ci		V <sub>I</sub> = 2.5 V or 0.5	V		3.5						pF	
Co		V <sub>O</sub> = 2.5 V or 0.5	5 V		7.5						pF	

<sup>\*</sup> On products compliant to MIL-PRF-38535, this parameter does not apply.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		SN54AE	3T16841	
		V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C	MIN MAX	UNIT
		MIN MAX		
t <sub>W</sub>	Pulse duration, LE high or low	4	4	ns
t <sub>su</sub>	Setup time, data before LE↓	3	3	ns
th	Hold time, data after LE↓	2.6	2.6	ns



<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ .

<sup>&</sup>lt;sup>‡</sup> This parameter is characterized, but not production tested.

<sup>§</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

<sup>¶</sup> This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			SN74ABT16841			
		$V_{CC} = 5 \text{ V},$ $T_A = 25^{\circ}\text{C}$ MIN		MIN	MAX	UNIT
		MIN	MAX	1		
t <sub>W</sub>	Pulse duration, LE high or low	4		4		ns
t <sub>su</sub>	Setup time, data before LE↓	1		1		ns
th	Hold time, data after LE↓	2		2		ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

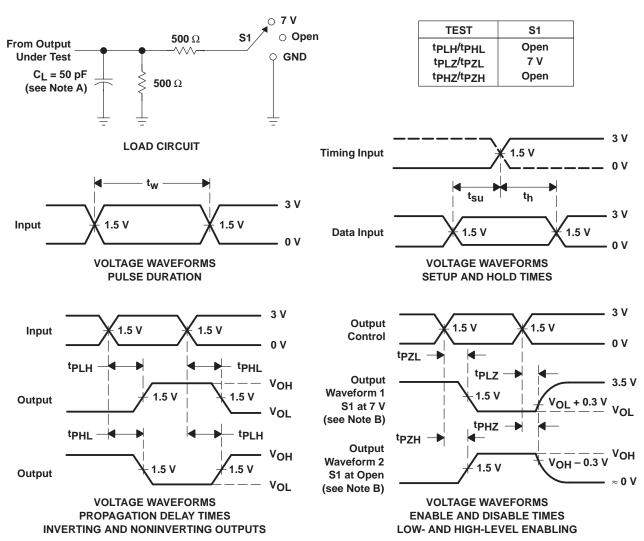
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>(</sub>	CC = 5 V A = 25°C	<i>'</i> ,	MIN	MAX	UNIT
			MIN	TYP	MAX			
t <sub>PLH</sub>	D	Q	1.1	3.2	4.3	1.1	5.7	20
t <sub>PHL</sub>			1.6	3.5	4.5	1.6	5.3	ns
<sup>t</sup> PLH	LE	Q	1.1	3.2	4.4	1.1	5.6	ns
<sup>t</sup> PHL		<u> </u>	1.6	3.4	5	1.6	5.5	115
<sup>t</sup> PZH	ŌĒ	DE Q	1.2	3.2	4.7	1.2	5.8	ns
t <sub>PZL</sub>	OE	ά	1.7	3.6	5	1.7	5.7	115
<sup>t</sup> PHZ	ŌĒ	Q	2.2	4.1	6.6	2.2	7.7	ns
<sup>t</sup> PLZ	OE .	ď	1.9	4.4	5.8	1.2	8.4	115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L$  = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t <sub>PLH</sub>	D	Q -	1.1	3.2	4.3	1.1	5	ns
t <sub>PHL</sub>			1.6	3.5	4.5	1.6	5.1	115
t <sub>PLH</sub>	LE	Q	1.1	3.2	4.4	1.1	5	ns
<sup>t</sup> PHL			1.6	3.4	4.6	1.6	5	115
<sup>t</sup> PZH	<del></del>	ŌĒ Q	1.2	3.2	4.7	1.2	5.7	ns
t <sub>PZL</sub>	OE		1.7	3.6	5	1.7	5.6	115
<sup>t</sup> PHZ	ŌĒ	Q	2.2	4.1	5.7	2.2	6.5	ns
tPLZ	OE .		1.9	4.4	5.8	1.9	7.1	115

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{Q}$  = 50  $\Omega$ ,  $t_{f}$   $\leq$  2.5 ns,  $t_{f}$   $\leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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